



IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant : Hisashi Ohtani
Serial No. : 10/657,137
Filed : September 9, 2003
Title : SEMICONDUCTOR INTEGRATED CIRCUIT AND FABRICATION METHOD
THEREOF

Art Unit : 2822
Examiner : Ida M. Soward
Confirmation No.: 1909

MAIL STOP AMENDMENT

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

INFORMATION DISCLOSURE STATEMENT

Applicants request consideration of the references listed on the attached PTO-1449 form. Under 37 C.F.R. § 1.98 (a)(2)(ii), only copies of foreign patent documents and/or non-patent literature are enclosed. Copies of any listed U.S. patents or U.S. patent application publications can be provided upon request.

This statement is being filed within three months of the filing date of a request for continued examination and before the receipt of an Office Action on the merits. Please apply any charges or credits to Deposit Account No. 06-1050.

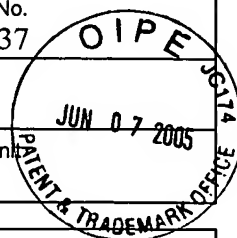
Respectfully submitted,

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Substitute Form PTO-1449 (Modified)	U.S. Department of Commerce Patent and Trademark Office	Attorney's Docket No. 07977-152003	Application No. 10/657,137
Information Disclosure Statement by Applicant (Use several sheets if necessary) (37 CFR §1.98(b))		Applicant Hisashi Ohtani	
		Filing Date September 9, 2003	Group Art Unit 2822



U.S. Patent Documents							
Examiner Initial	Desig. ID	Document Number	Publication Date	Patentee	Class	Subclass	Filing Date If Appropriate
	AA	2003/0042559 A1	03/06/2003	TAKEMURA et al.			12/28/2001
	AB	2005/0040476 A1	02/24/2005	TAKEMURA et al.			09/08/2004
	AC	5,292,675	03/08/1994	CODAMA			12/14/1992
	AD	5,306,651	04/26/1994	MASUMO et al.			05/10/1991
	AE	5,468,987	11/21/1995	YAMAZAKI et al.			03/25/1993
	AF	5,719,065	02/17/1998	TAKEMURA et al.			09/28/1994
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	AH	5,917,225	06/29/1999	YAMAZAKI et al.			09/26/1996
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Foreign Patent Documents or Published Foreign Patent Applications								
Examiner Initial	Desig. ID	Document Number	Publication Date	Country or Patent Office	Class	Subclass	Translation	
							Yes	No
	AL	56-111258	09/02/1981	JAPAN			Full	
	AM	03-095938	04/22/1991	JAPAN			Full	
	AN	03-095939	04/22/1991	JAPAN			Full	
	AO	03-020046	01/29/1991	JAPAN			Full	
	AP							

Other Documents (include Author, Title, Date, and Place of Publication)		
Examiner Initial	Desig. ID	Document
	AQ	
	AR	
	AS	
	AT	

Examiner Signature	Date Considered
EXAMINER: Initials citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.	